

600V N-Channel MOSFET

Description

The MSD4N60 is a N-channel enhancement-mode MOSFET, providing the designer with the best combination of fast switching, ruggedized device design, low on-resistance and cost effectiveness. The TO-252 package is universally preferred for all commercial-industrial applications

Features

- · Low On Resistance
- Simple Drive Requirement
- · Low Gate Charge
- Fast Switching Characteristic
- RoHS compliant package

Application

- · Low power battery chargers
- Switch mode power supply (SMPS)
- DC-AC converters.

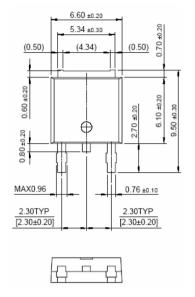
Packing & Order Information

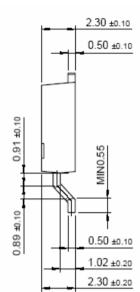
Part No./ R: 2,500/Reel

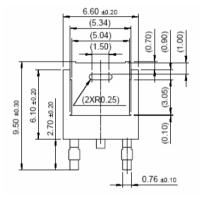
Part No./ T: 80/Tube, 4,000/Box



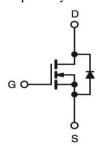








Graphic symbol



MAXIMUM RATINGS AND ELECTRICAL CHARACTERISTICS

Absolute Maximum Ratings (Tc=25°C unless otherwise noted)						
Symbol	Parameter	Value	Unit			
V_{DSS}	Drain-Source Voltage	600	V			
V_{GS}	Gate-Source Voltage	±30	V			
I_D	Continuous Drain Current (TC=25°C)	4.5	A			
	Continuous Drain Current (T _C =100°C)	2.6	A			
I_{DM}	Pulsed Drain Current	18	A			



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Absolute Maximum Ratings (Tc=25°C unless otherwise noted)					
Symbol	Parameter	Value	Unit		
EAS	Single Pulsed Avalanche Energy	33	mJ		
I _{AR}	Avalanche Current	4.0	A		
EAR	Repetitive Avalanche Energy	10	mJ		
dV/dt	Peak Diode Recovery dV/dt	4.5	V/ns		
P_D	Power Dissipation (T _C =25°C)	31	W		
	Derating Factor above 25 °C	0.25	W		
Тл	Storage Temperature	150	°C		
T_{L}	Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds	300	°C		

Note:

- 1. Repetitive rating; pulse width limited by maximum junction temperature.
- 2. I_{AS} =4A, V_{DD} =50V, L=8mH, V_{G} =10V, starting TJ=+25°C.
- 3. I_{SD}≤4A, dI/dt≤100A/µs, VDD≤BVDSS, starting TJ=+25°C.

Thermal Resistance Characteristics (Tc=25°C unless otherwise noted)							
Symbol	Do no motor	Value			T I		
	Parameter	Min.	Typ.	Max.	Units		
Rөлс	Thermal Resistance, Junction-to-Case			2.8	0C/W		
R _{θJ A}	Thermal Resistance, Junction-to- Ambient			50	°C/W		

Off Characteristics						
Symbol	Parameter	Test Conditions	Min	Тур.	Max.	Units
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS}=0~V$, $I_D\text{=}250\mu\text{A}$	600			V
ΔBV_{DSS} $/\Delta T_J$	Breakdown Voltage Temperature Coefficient	I_D = 250 μ A, Referenced to 25 $^{\circ}$ C		0.60		V/°C
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS}=V_{GS}\;,\;I_D\!=250\mu A$	2.0		4.0	V
IDSS	Drain-Source Leakage Current	$V_{DS} = 600 \text{ V}, V_{GS} = 0 \text{ V}$ $V_{DS} = 480 \text{ V}, T_C = 125 ^{\circ}\text{C}$			1 10	uA
Igss	Gate-Body Leakage Forward	$V_{GS} = \pm 30$			±100	nA
$R_{\mathrm{DS}(\mathrm{ON})}$	Static Drain-Source On-Resistance	$V_{GS} = 10 \text{ V}$, $I_D = 2.25 \text{ A}$		2.0	2.5	Ω



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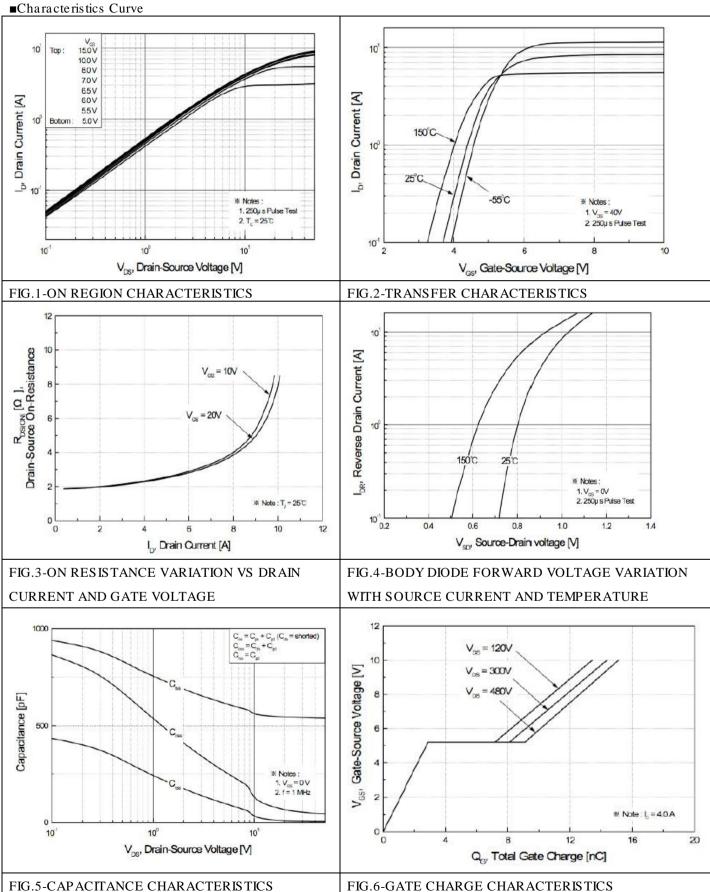
Dynamic Characteristics						
Symbol	Parameter	Test Conditions	Min	Тур.	Max.	Units
C_{ISS}	Input Capacitance			560		pF
Coss	Output Capacitance	$V_{DS} = 25 \text{ V}, V_{GS} = 0 \text{ V},$ F = 1.0 MHz		55		pF
C_{RSS}	Reverse Transfer Capacitance	$\Gamma = 1.0$ WIFIZ		7		pF
$t_{d(on)}$	Turn-On Time			10	30	ns
$t_{\rm r}$	Turn-On Time	$V_{DD} = 300 \text{ V, } I_D = 4.5 \text{ A,}$ $R_G = 25 \Omega \text{ , } V_{GS} = 10 \text{ V}$		40	80	ns
$t_{d(\rm off)} \\$	Turn-Off Delay Time			40	100	ns
tf	Turn-Off Fall Time			50	90	ns
Qg	Total Gate Charge			16		nC
Q_{gs}	Gate-Source Charge	$V_{DD} = 480 \text{ V}, I_D = 4.5 \text{ A},$ $V_{GS} = 10 \text{ V}$		2.5		nC
Q_{gd}	Gate-Drain Charge			6.5		nC

Source-Drain Diode						
Symbol	Parameter	Test Conditions	Min	Typ.	Max.	Units
Is		AD AG O			4.0	
I _{SM}		VD = VG = 0			16	A
V _{SD}		$I_S = 4.0 A$, $V_{GS} = 0 V$			1.4	V
t _{rr}		$I_F = 4.0 \text{ A}, V_{GS} = 0 \text{ V}$		270		ns
Qrr		$diF/dt = 100A/\mu s$		18		uC

^{*}Pulse Test : Pulse Width ≤300µs, Duty Cycle≤2%



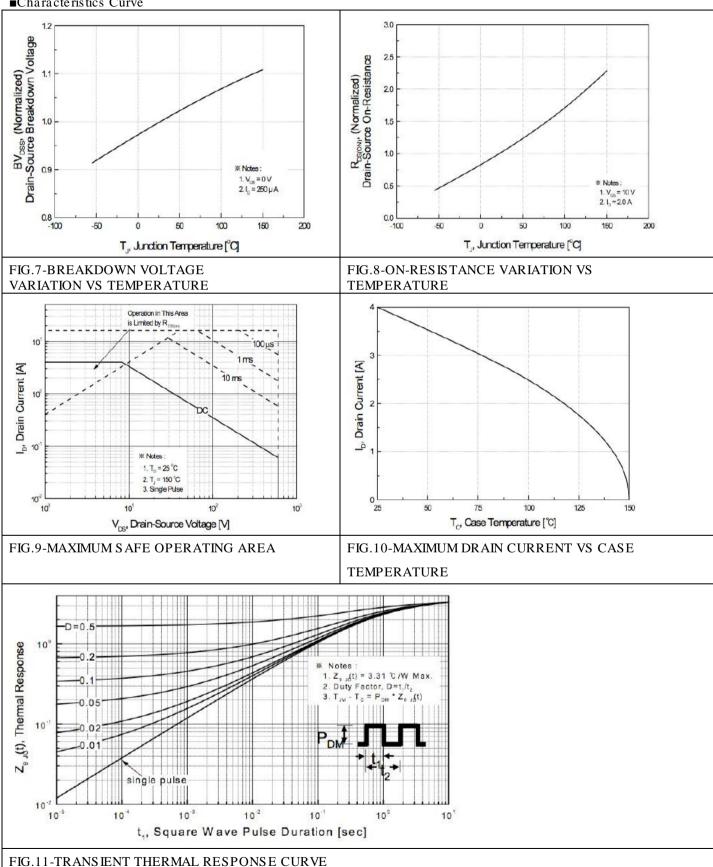
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■Characteristics Curve





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■Characteristics Test Circuit & Waveform

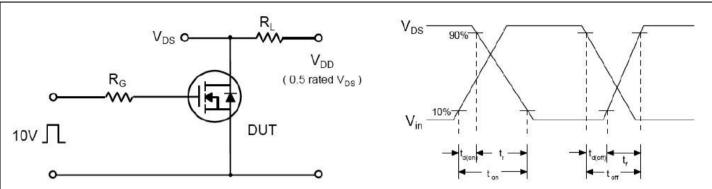


Fig 12. Resistive Switching Test Circuit & Waveforms

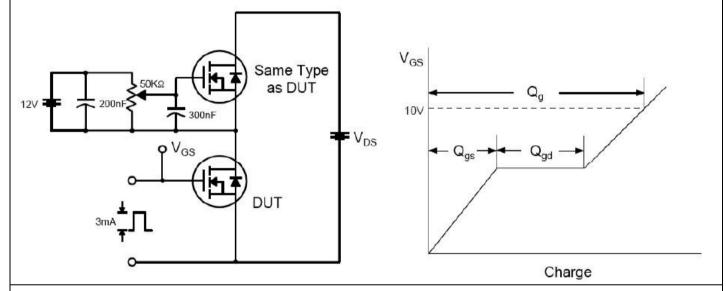


Fig 13. Gate Charge Test Circuit & Waveform

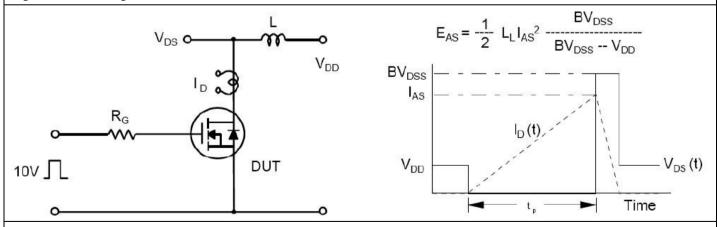


Fig 14. Unclamped Inductive Switching Test Circuit & Waveforms



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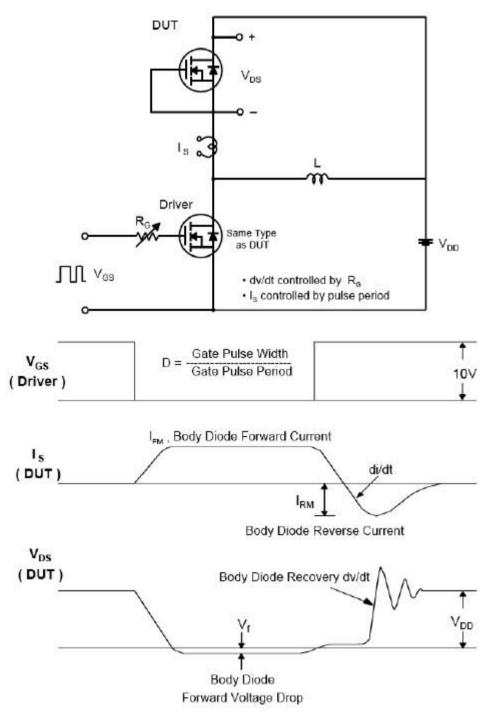


Fig 15. Peak Diode Recovery dv/dt Test Circuit & Waveforms



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